

UNISONIC TECHNOLOGIES CO., LTD

3NM120-Q Preliminary Power MOSFET

3.0A, 1200V N-CHANNEL SUPER-JUNCTION MOSFET

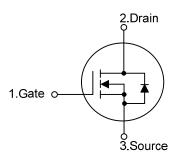
■ DESCRIPTION

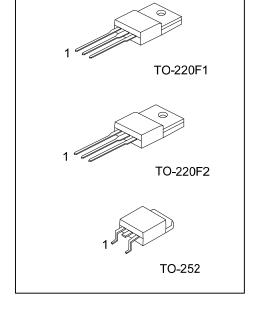
The UTC **3NM120-Q** is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at AC-DC converters for power applications.

■ FEATURES

- * $R_{DS(ON)} \le 5.6 \Omega$ @ $V_{GS}=10V$, $I_D=1.5A$
- * High Switching Speed



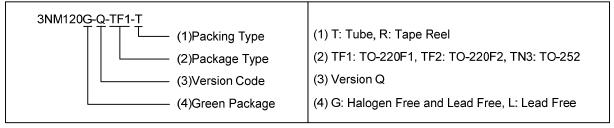




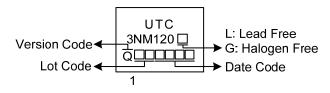
■ ORDERING INFORMATION

Ordering Number		Dookogo	Pin	Assignm	Dooking		
Lead Free	Halogen Free	Package	1	2	3	Packing	
3NM120L-Q-TF1-T	3NM120G-Q-TF1-T	TO-220F1	G	D	S	Tube	
3NM120L-Q-TF2-T	3NM120G-Q-TF2-T	TO-220F2	G	D	S	Tube	
3NM120L-Q-TN3-R	3NM120G-Q-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING



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■ ABSOLUTE MAXIMUM RATINGS (unless otherwise specified)

PARAMETER			SYMBOL	RATINGS	UNIT
Orain-Source Voltage		V _{DSS}	1200	V	
Gate-Source Voltage		V _{GSS}	±30	V	
Continuous Drain Current	Continuous		I _D	3	Α
	Pulsed		I _{DM}	6	Α
Avalanche Energy	Single Pulsed (Note 3)		E _{AS}	65	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	2	V/ns	
Power Dissipation	TO-220F1/TO-220F2			22	W
	11()-252	Steady State	P _D	24	W
		t ≤ 5s		45	W
Junction Temperature		TJ	+150	°C	
Storage Temperature		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 100mH, I_{AS} = 1.14A, V_{DD} = 50V, R_{G} = 25 Ω Starting T_{J} = 25°C
- 4. $I_{SD} \le 3.0 \text{A}$, di/dt $\le 200 \text{A}/\mu\text{s}$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}\text{C}$

■ THERMAL DATA

PARAMETER		SYMBOL	RATING	UNIT	
Junction to Ambient	TO-220F1/TO-220F2		θја	62.5	°C/W
	TO-252			110	°C/W
Junction to Case	TO-220F1/TO-220F2			5.68	°C/W
	TO-252	Steady State	θυς	5.2 (Note)	°C/W
		t ≤ 5s		2.77 (Note)	°C/W

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

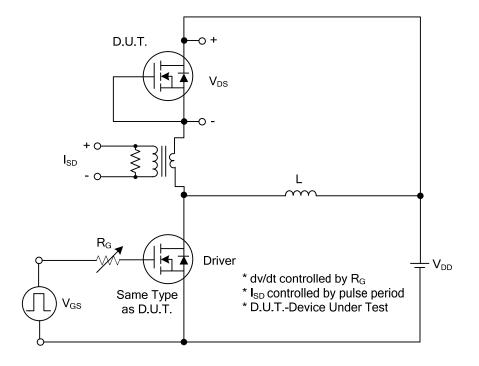
■ ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFF CHARACTERISTICS		•						
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =250μA, V _{GS} =0V	1200			V		
Drain-Source Leakage Current	I _{DSS}	V _{DS} =1200V, V _{GS} =0V			10	μΑ		
Coto Source Lookage Current	d ,	V_{GS} =+30V, V_{DS} =0V			+100	nA		
Gate-Source Leakage Current Revers	e I _{GSS}	V _{GS} =-30V, V _{DS} =0V			-100	nA		
ON CHARACTERISTICS	ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(TH)}$	V _{DS} =V _{GS} , I _D =250µA	2.5		4.5	V		
Static Drain-Source On-State Resistanc	e R _{DS(ON)}	V _{GS} =10V, I _D =1.5A			5.6	Ω		
DYNAMIC PARAMETERS			_	-				
Input Capacitance	C _{ISS}			290		рF		
Output Capacitance	Coss	V _{GS} =0V, V _{DS} =50V, f=1.0MHz		22		pF		
Reverse Transfer Capacitance	C _{RSS}			2.3		pF		
SWITCHING PARAMETERS			_	-				
Total Gate Charge	Q_G	V _{DS} =960V, V _{GS} =10V, I _D =3.0A (Note 1, 2)		18		nC		
Gate to Source Charge	Q_GS			6		nC		
Gate to Drain Charge	Q_{GD}	(Note 1, 2)		5		nC		
Turn-ON Delay Time	t _{D(ON)}			6.4		ns		
Rise Time	t _R	V _{DD} =100V, V _{GS} =10V, I _D =3.0A,		17		ns		
Turn-OFF Delay Time	t _{D(OFF)}	R _G =25Ω (Note 1, 2)		38		ns		
Fall-Time	t _F			32		ns		
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Curre	ent Is				3	Α		
Maximum Body-Diode Pulsed Current	Ism				6	Α		
Drain-Source Diode Forward Voltage	V _{SD}	I _S =3.0A, V _{GS} =0V			1.4	V		
Body Diode Reverse Recovery Time	t _{rr}	I _S =3.0A, V _{GS} =0V,		516		ns		
Reverse Recovery Charge	Qrr	dI _F /dt=100A/µs (Note 1)				μC		

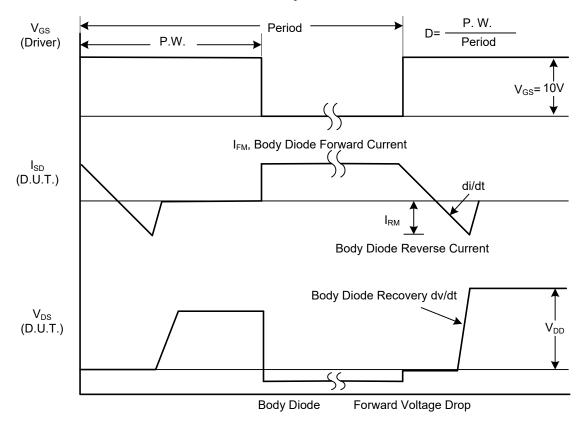
Notes: 1. Pulse Test: Pulse width ≤ 1200µs, Duty cycle ≤ 2%.

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

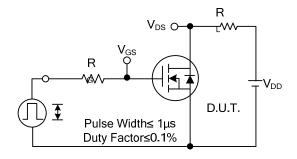


Peak Diode Recovery dv/dt Test Circuit

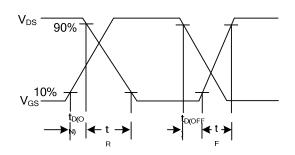


Peak Diode Recovery dv/dt Waveforms

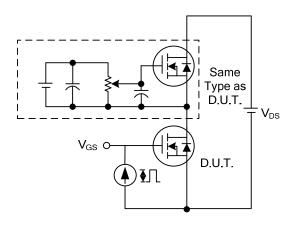
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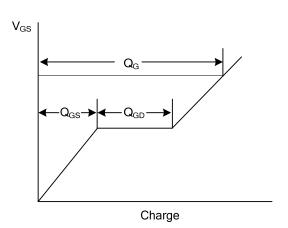
Switching Test Circuit



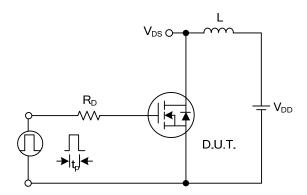
Switching Waveforms



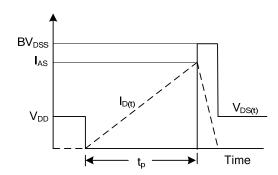
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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